Abstracts

Non-contact internal-MMIC measurement using scanning force probing

C.J. Falkingham, I.H. Edwards and G.E. Bridges. "Non-contact internal-MMIC measurement using scanning force probing." 2000 MTT-S International Microwave Symposium Digest 00.3 (2000 Vol. III [MWSYM]): 1619-1622.

A non-contacting probe capable of internal vector measurements of MMICs is presented. Accurate internal amplitude and phase measurements can be made with micrometer spatial resolution, <1 fF loading and without the need to depassivate the circuit. A 10 GHz bandwidth probe is presented.

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